

UNISONIC TECHNOLOGIES CO., LTD

22N20 Preliminary Power MOSFET

22A, 200V N-CHANNEL POWER MOSFET

■ DESCRIPTION

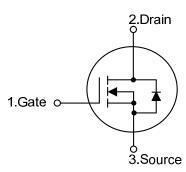
The UTC **22N20** is an N-channel enhancement mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology is specialized in allowing a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC **22N20** is universally applied in low voltage such as automotive, high efficiency switching for DC/DC converters and DC motor control.

■ FEATURES

- * Fast switching
- * $R_{DS(on)}$ = 0.14 Ω @ V_{GS} = 10 V
- * Typically 20nC low gate charge
- * 100% avalanche tested
- * Typically 25pF Low C_{RSS}
- * Improved dv/dt capability

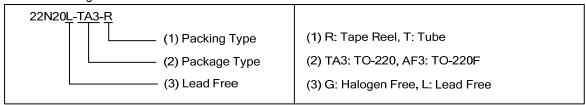
■ SYMBOL

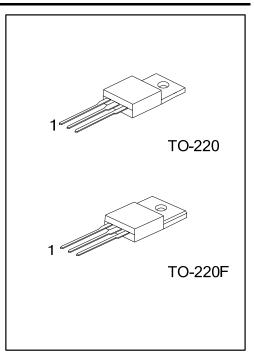


■ ORDERING INFORMATION

Ordering Number		Dealtage	Pin Assignment			Doolsing	
Lead Free	Halogen Free	Package	1	2	3	Packing	
22N20L-TA3-T	22N20G-TA3-T	TO-220	G	D	S	Tube	
22N20L-TF3-T	22N20G-TF3-T	TO-220F	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source





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■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	200	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Continuous ((T _C =25°C)	I_D	22	Α
Drain Current	Pulsed (Note 2)		I _{DM}	88	Α
Avalanche Energy	Single Pulsed (Note 3)		E _{AS}	250	mJ
Power Dissipation (T _C =25°C)		TO-220		156	W
		TO-220F	P _D	50	l vv
Derate above 25°C		TO-220		1.25	14//90
		TO-220F		0.4	W/°C
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55~+150	°C	

- Note: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

 Absolute maximum ratings are stress ratings only and functional device operation is not implied.
 - 2. Repetitive Rating: Pulse width limited by maximum junction temperature
 - 3. L =0.85mH, I_{AS} = 21A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT	
Junction to Ambient	TO-220/TO-220F	θ_{JA}	62.5	°C/W	
lunation to Cook	TO-220	0	0.8	°C/M	
Junction to Case	TO-220F	θ_{JC}	2.5	°C/W	

■ **ELECTRICAL CHARACTERISTICS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	200			V
Breakdown Voltage Temperature Coefficient		$\triangle BV_{DSS}/\triangle T_{J}$	Reference to 25°C, I _D =250µA		0.25		V/°C
Drain-Source Leakage Current			V _{DS} =200V, V _{GS} =0V			1	
		I _{DSS}	V _{DS} =160V, T _C =125°C			10	μΑ
Cata Sauraa Laakaga Current	Forward		V _{GS} =+30V, V _{DS} =0V			+100	nA
Gate- Source Leakage Current	Reverse	I _{GSS}	V _{GS} =-30V, V _{DS} =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	3.0		5.0	V
Static Drain-Source On-State Re	esistance	R _{DS(ON)}	V _{GS} =10V, I _D =11A		0.12	0.14	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}			1700	2200	pF
Output Capacitance Reverse Transfer Capacitance		Coss	V_{GS} =0V, V_{DS} =25V, f=1.0MHz		220	290	pF
		C_{RSS}			30	40	pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	\\ -40\\ \\ -460\\ -22A		27	35	nC
Gate to Source Charge		Q_GS	V _{GS} =10V, V _{DS} =160V, I _D =22A		5.8		nC
Gate to Drain Charge		Q_GD	(Note 1, 2)		11.2		nC
Turn-ON Delay Time		$t_{D(ON)}$			35	80	ns
Rise Time		t_R	V_{DD} =100V, I_{D} =22A, R_{G} =25 Ω		300	610	ns
Turn-OFF Delay Time		t _{D(OFF)}	(Note 1, 2)		130	270	ns
Fall-Time		t _F			180	370	ns

■ ELECTRICAL CHARACTERISTICS(Cont.)

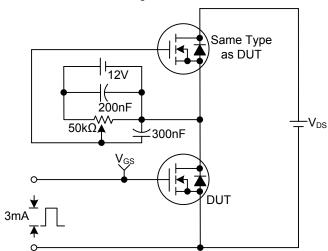
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current	Is				22	Α	
Maximum Body-Diode Pulsed Current	I _{SM}				88	Α	
Drain-Source Diode Forward Voltage	V_{SD}	I _S =22A, V _{GS} =0V			1.5	V	

Note: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

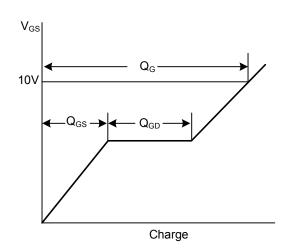
2. Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

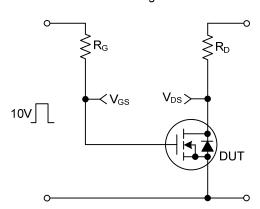
Gate Charge Test Circuit



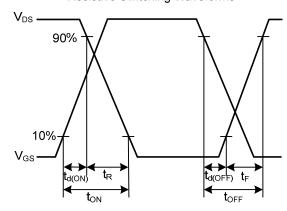
Gate Charge Waveforms



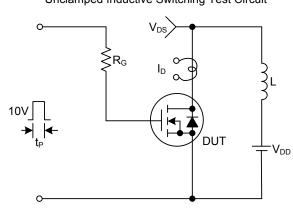
Resistive Switching Test Circuit



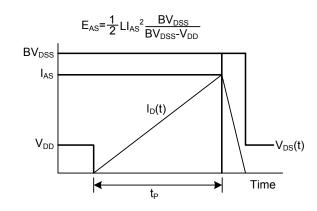
Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit

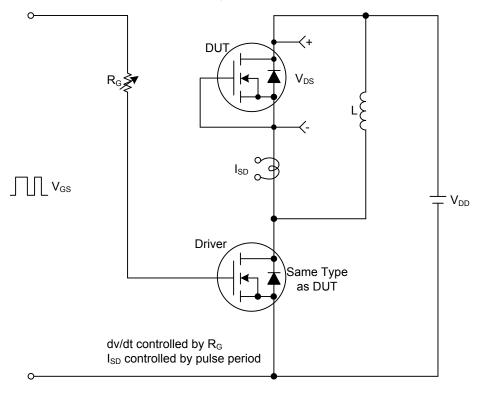


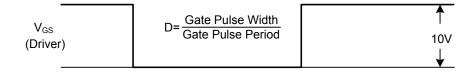
Unclamped Inductive Switching Waveforms

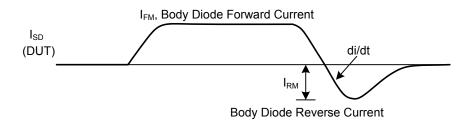


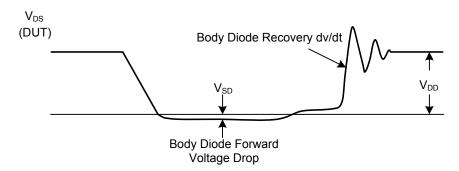
■ TEST CIRCUITS AND WAVEFORMS(Cont.)

Peak Diode Recovery dv/dt Test Circuit & Waveforms









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